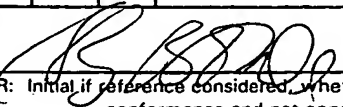


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LIST OF PRIOR ART CITED BY APPLICANT (Use several sheets if necessary)				Applicant: Dr. Frederik Bijkerk et al.		Group:	
				Filing Date: November 12, 2003			
				U.S. PATENT DOCUMENTS			
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GAB	AA	5,052,033	September 1991	Ikeda et al.			
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GAB	AL	WO 99/24851	May 20, 1999	WIPO			
	AM	08122496	May 17, 1996	JP			
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GAB	AR	J.H. Underwood et al., <i>Tarnishing of Mo/Si multilayer x-ray mirrors</i> , Applied Optics, vol. 32, 1993, p. 6985-6990					
↓	AS	C. Montcalm et al., <i>Multilayer reflective coatings for extreme-ultraviolet lithography</i> , SPIE, vol. 3331, (1998) p. 42-51					
GAB	AT	M. Cilia et al., <i>Ni/Si based multilayer for the reflection of soft x rays in the "water window"</i> , J. Appl-Phys., 82 (9), 1997, p. 4137-4142					
EXAMINER B. B. 870		DATE CONSIDERED 3/15/06					
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